

Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/810,749	KIM ET AL.
	Examiner	Art Unit
	Hien N. Nguyen	2824

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
365	205	9/6/2005	HN
365	207	9/6/2005	HN
365	222	9/6/2005	HN